



- ★ Super Low Gate Charge
- ★ 100% EAS Guaranteed
- ★ Green Device Available
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology

### Product Summary

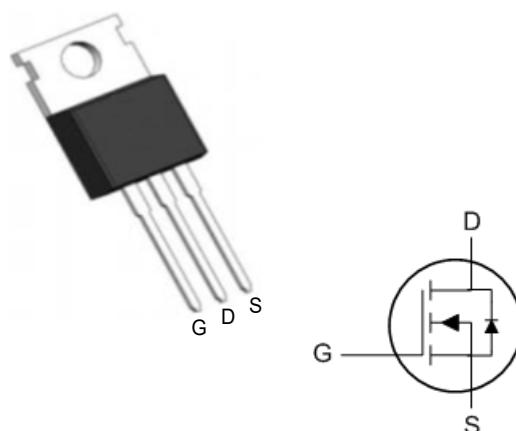
BVDSS	RDS(ON)	ID
40V	2.4mΩ	150A

### Description

The XXWP150N04T is the high performance complementary N-ch MOSFETs with high cell density, which provide excellent RDS(ON) and gate charge for most of the synchronous buck converter applications.

The XXWP150N04T meet the RoHS and Green Product requirement 100% EAS guaranteed with full function reliability approved.

### TO220AB Pin Configuration



### Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	40	V
V <sub>GS</sub>	Gate-Source Voltage	±20	V
I <sub>D</sub> @T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1,6</sup>	150	A
I <sub>D</sub> @T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1,6</sup>	85	A
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	560	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	726	mJ
I <sub>AS</sub>	Avalanche Current	---	A
P <sub>D</sub> @T <sub>C</sub> =25°C	Total Power Dissipation <sup>4</sup>	115	W
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	°C

### Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
R <sub>θJA</sub>	Thermal Resistance Junction-Ambient <sup>1</sup>	---	---	°C/W
R <sub>θJC</sub>	Thermal Resistance Junction-Case <sup>1</sup>	---	1.3	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$ , unless otherwise noted)**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$ , $I_D=250\mu\text{A}$	40	---	---	V
$\Delta BV_{DSS}/\Delta T_J$	$BV_{DSS}$ Temperature Coefficient	Reference to $25^\circ\text{C}$ , $I_D=1\text{mA}$	---	---	---	$\text{V}^\circ\text{C}$
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}=10\text{V}$ , $I_D=20\text{A}$	---	2.4	3.1	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}$ , $I_D=20\text{A}$	---	3.5	4.7	
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{GS}=V_{DS}$ , $I_D=250\mu\text{A}$	1.0	1.7	2.5	V
$\Delta V_{GS(\text{th})}$	$V_{GS(\text{th})}$ Temperature Coefficient		---	---	---	$\text{mV}^\circ\text{C}$
$I_{DSS}$	Drain-Source Leakage Current	$V_{DS}=40\text{V}$ , $V_{GS}=0\text{V}$ , $T_J=25^\circ\text{C}$	---	---	1	$\text{uA}$
		$V_{DS}=40\text{V}$ , $V_{GS}=0\text{V}$ , $T_J=100^\circ\text{C}$	---	---	100	
$I_{GSS}$	Gate-Source Leakage Current	$V_{GS}=\pm 20\text{V}$ , $V_{DS}=0\text{V}$	---	---	$\pm 100$	nA
$g_{fs}$	Forward Transconductance	$V_{DS}=5\text{V}$ , $I_D=20\text{A}$	---	38	---	S
$R_g$	Gate Resistance	$V_{DS}=0\text{V}$ , $V_{GS}=0\text{V}$ , $f=1\text{MHz}$	---	0.67	---	$\Omega$
$Q_g$	Total Gate Charge	$V_{DS}=20\text{V}$ , $V_{GS}=10\text{V}$ , $I_D=20\text{A}$	---	112	---	$\text{nC}$
$Q_{gs}$	Gate-Source Charge		---	16.7	---	
$Q_{gd}$	Gate-Drain Charge		---	26.5	---	
$T_{d(on)}$	Turn-On Delay Time	$V_{GS}=10\text{V}$ , $VDD=20\text{V}$ , $RG=3\Omega$ , $ID=10\text{A}$	---	18	---	$\text{ns}$
$T_r$	Rise Time		---	4.4	---	
$T_{d(off)}$	Turn-Off Delay Time		---	67	---	
$T_f$	Fall Time		---	9.5	---	
$C_{iss}$	Input Capacitance		---	6460	---	$\text{pF}$
$C_{oss}$	Output Capacitance	$V_{DS}=20\text{V}$ , $V_{GS}=0\text{V}$ , $f=1\text{MHz}$	---	455	---	
$C_{rss}$	Reverse Transfer Capacitance		---	276	---	

**Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$I_s$	Continuous Source Current <sup>1,5</sup>	$V_G=V_D=0\text{V}$ , Force Current	---	---	150	A
$V_{SD}$	Diode Forward Voltage <sup>2</sup>	$V_{GS}=0\text{V}$ , $I_s=1\text{A}$ , $T_J=25^\circ\text{C}$	---	---	1.2	V

Note :

 The data is tested by a surface mounted on a  $1\text{inch}^2$  FR-4 board with  $2\text{OZ}$  copper.

 The data is tested by a pulsed pulse width  $\leq 300\text{us}$  duty cycle  $\leq 2\%$ .

 The EAS data shows Max. rating . The test condition is  $T_J=25^\circ\text{C}$ ,  $VDD=40\text{V}$ ,  $VG=10\text{V}$ ,  $Rg=25\Omega$ ,  $L=0.5\text{mH}$ .

 The power dissipation is limited by  $150^\circ\text{C}$  junction temperature.

 The data is theoretically the same as  $A_{DQ}$  and  $A_{DMA}$ . In real applications, it should be limited by total power dissipation.

### Typical Electrical And Thermal Characteristics (Curves)

Figure 1. Output Characteristics

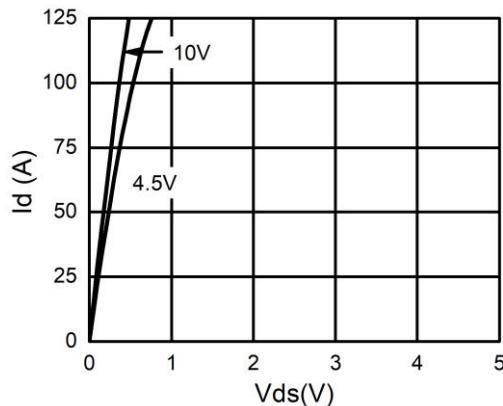


Figure 2. Transfer Characteristics

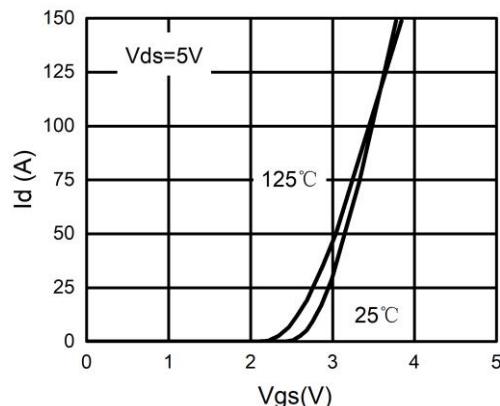


Figure 3. Power Dissipation

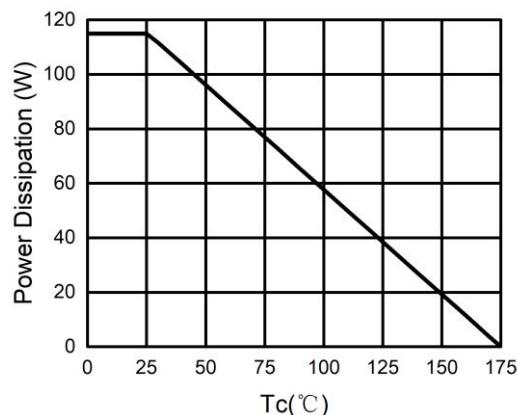


Figure 4. Drain Current

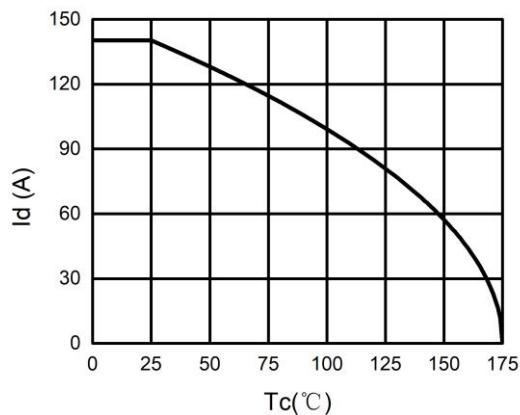


Figure 5. BV<sub>DSS</sub> vs Junction Temperature

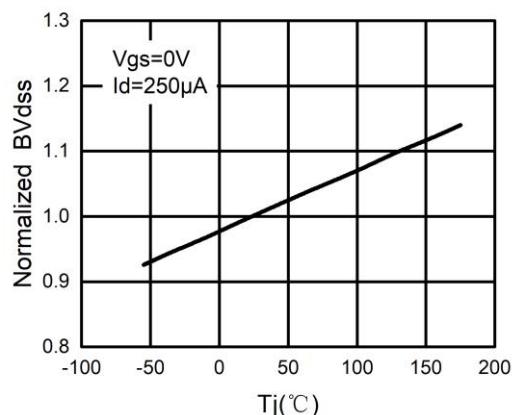
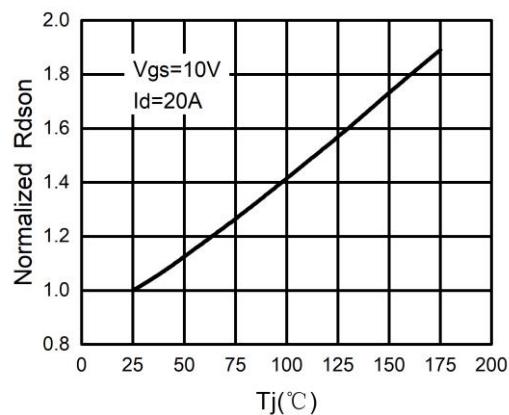
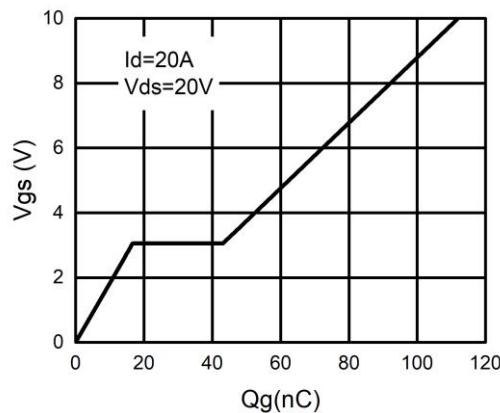
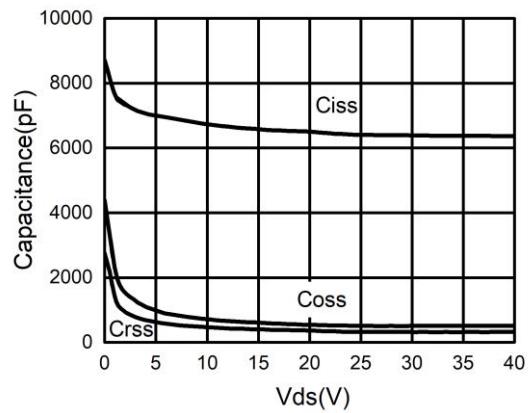
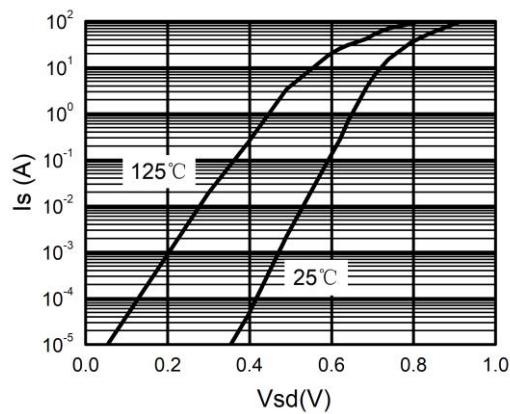
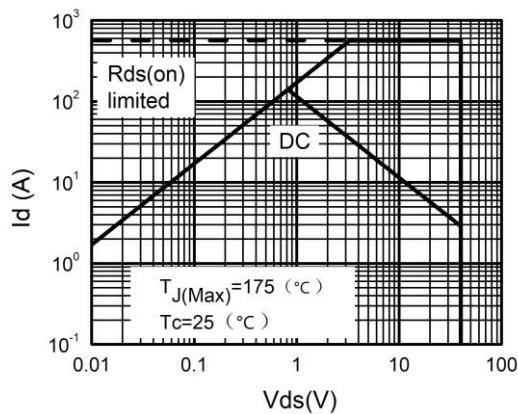
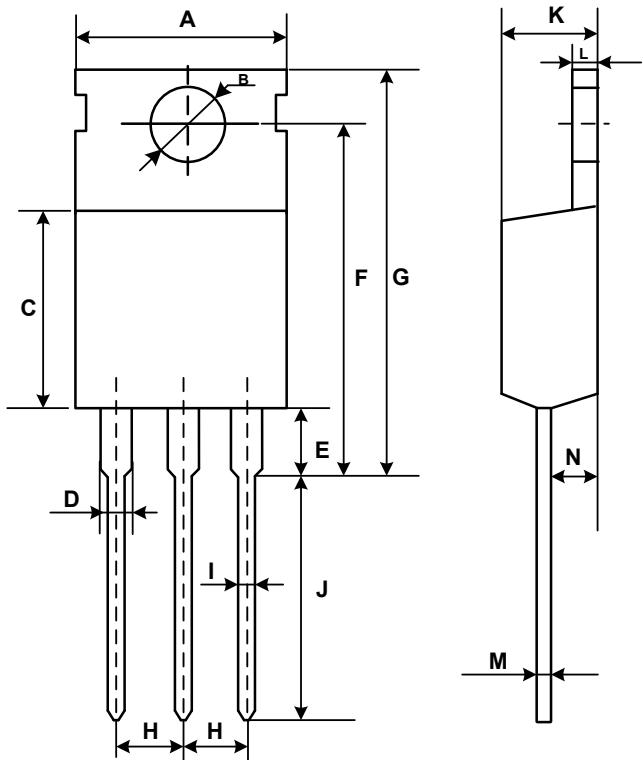


Figure 6. R<sub>DS(ON)</sub> vs Junction Temperature



**Figure 7. Gate Charge Waveforms**

**Figure 8. Capacitance**

**Figure 9. Body-Diode Characteristics**

**Figure 10. Maximum Safe Operating Area**


**Mechanical Dimensions for TO-220**
**COMMON DIMENSIONS**


SYMBOL	MM	
	MIN	MAX
A	9.70	10.30
B	3.40	3.80
C	8.80	9.40
D	1.17	1.47
E	2.60	3.50
F	15.10	16.70
G	19.55MAX	
H	2.54REF	
I	0.70	0.95
J	9.35	11.00
K	4.30	4.77
L	1.20	1.45
M	0.40	0.65
N	2.20	2.60